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11-9-2015

# KMPR Delamination Resistance Study Report

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#### Keywords

KMPR, Delamination, Soft Lithography

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# **KMPR Delamination Resistance Study Report**

Updated on 11/09/2015

### **Critical Factors**

- No silicon wafer pretreatments were required to minimize KMPR photoresist delamination during PDMS casting and peeling for feature sizes on the order of 10 um or larger
- Proper exposure time is also necessary to minimize delamination
  - See ABM Operating Procedure binder for updated lamp power output through glass, 365nm filter, and polyfilm material.
- Resistance to delamination was achieved at sub-optimal exposure dosage when the wafer was pretreated by BOE rinse followed by dehydration.

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### Goal

Test KMPR resistance to delamination induced by PDMS casting and peeling under various wafer pretreatment conditions.

### Materials

- KMPR-1025 (produced by thinning KMPR-1050)
- SU8 thinner
- 4 inch diameter silicon wafers
- Line photomask (transparency film)
  - 10 um lines, 50 um troughs ("10X50")
  - 25 um lines, 50 um troughs ("25X50")
- Isopropyl alcohol (IPA)
- Acetone
- Buffered oxide etchant (BOE) in HF hood. You must be HF hood trained before working with BOE. Speak with Eric Johnston or Kyle Keenan to arrange training.

### Equipment

- Laurell spinner
- Two hotplates
- ABM mask aligner



#### Protocol

#### Preparation of KMPR-1025 equivalent from KMPR-1050 stock

- 1. Weighed out 135.4 g KMPR1050
- 2. Calculated weight of thinner to add via:
  - a. Wthinner = [(% solids initial /% solids final) 1]\*Wresist
  - b. Wthinner = [(67.3/63.8) 1]\*135.4 g = 7.4 g thinner
- 3. Mixed with glass stirring rod in beaker for ~ 10 min until homogeneous
- 4. Aliquoted using Teflon funnel into resist bottles
- 5. Allowed bottles to degas by resting at RT overnight
- 6. Stored bottles in -20C freezer for long term storage. Before master generation, allowed bottles to warm to RT overnight.

#### Wafer pretreatments tested:

- 1. No treatment (including dehydration)
- 2. Dehydration for at least 10 minutes at 200C
- 3. Acetone wash + IPA wash + nitrogen blow-dry + minimum 10 min dehydration 200C
- 4. 2 min BOE wash+ 2 min rinse in overflow bath + nitrogen blow-dry + minimum 10 min dehydration 200C

### KMPR spinning

- 1. Set spin parameters:
  - a. Vacuum = "req"
  - b. Step 1 of 2: 500 rpm, accel = "100", 30 sec
  - c. Setp 2 of 2: 3000 rpm, accel = "500", 30 sec
    - i. F40 Filmetrics measurement indicates these settings result in an approximately 20 um thick layer of resist
- 2. Mounted wafer and ensure centered
- 3. Poured photoresist without air entrapment to ~ 50 mm diameter
- 4. Spun the wafer
- 5. Transferred spun wafer to 95C hot plate for 10 min soft bake
- 6. If performing multiple spins, wiped spinner hood between wafers to prevent excess KMPR from dripping onto samples



**KMPR Delamination Resistance Study Report** 

Resist exposure and development

- 1. Started the ABM UV lamp (channel A). After suitable warmup period, measured bulb exposure power:
  - a. Using power meter set to channel A, measured power through transparency material, glass blank, and Omega Optical filter: 13.9 mW/cm<sup>2</sup>
    - b. Computed required exposure time:572.5 mJ/cm<sup>2</sup> / 13.9 mW/cm<sup>2</sup> = 41.2 sec
- 2. Mounted wafer, transparency, aluminum foil aperture to block exposure of extraneous regions
- 3. Contacted to glass blank with leveling
- 4. Rested Omega Optical filter on top of glass blank
- 5. Exposed lines for 31.2 sec, 41.2 sec, and 51.2 sec respectively
- 6. Post-exposure bake 95C for 2 min
- 7. Developed in bath of SU-8 developer for 5-10 min with periodic agitation
- 8. Rinsed in IPA and nitrogen blow-dry





#### PDMS Casting and Peeling

- Placed wafers in aluminum foil dishes of appropriate depth
- Mixed ~ 50 g of PDMS at 10:1 base:cure by weight ratio per wafer and degassed under vacuum until clear (~ 45 min)
- Poured PDMS to a depth of 7 mm over each wafer on a level aluminum block
- Transferred block to preheated 100C convection oven
- Cured PDMS for 70 min
- Allowed wafers to cool to RT
- Using a new razor blade manually excised PDMS above the KMPR mastered lines and peeled
- Inspected wafer and peeled PDMS for evidence of resist delamination

#### Results

Wafer Treatment	Plateau Length um	Trough Length um	Exposure Length		
			31.2 s	41.2 s	51.2 s
No Treatment	25	50	Pass	Pass	Pass
	10	50	Delamination	Pass	Pass
Dehydration	25	50	Pass	Pass	Pass
	10	50	Delamination	Pass	Pass
Acetone+IPA+Dehydration	25	50	Pass	Pass	Pass
	10	50	Delamination	Pass	Pass
BOE + Dehydration	25	50	Pass	Pass	Pass
	10	50	Pass	Pass	Pass

Table 1. 01/17/2014 results of delamination study performed on 12/06/2013 KMPR masters. Study was conducted by casting 10:1 (base:cure by weight) PDMS slabs to a depth of 7 mm and curing at 100 deg C for 70 min. After wafers cooled to RT, PDMS slabs were manually peeled from the master. Post-peel masters were inspected under an optical microscope for evidence of KMPR delamination. Out of all conditions tested, the BOE pre-treated wafer was the most robust in withstanding PDMS casting.